## The NSLS-II Deposition Laboratory

## Ray Conley<sup>\*1</sup>, Nathalie Bouet<sup>a</sup>, James Biancarosa<sup>a</sup>, Qun Shen<sup>a</sup> <sup>a</sup>Experimental Facilities Division, NSLS-II, Brookhaven National Laboratory, Upton, NY 11973

## ABSTRACT

The new NSLS-II<sup>[1]</sup> deposition laboratory has been commissioned to include various thin-film characterization equipment and a specialized deposition system with the primary goal of producing wedged multilayer Laue lens<sup>[2,3]</sup> (MLL), a new type of x-ray optic with the potential for an unprecedented level of x-ray nanofocusing. This unique deposition system contains many design features in order to facilitate growth of combined depth-graded and laterally-graded multilayers with precise thickness control over many thousands of layers, providing total film growth in one run of up to 100µm thick or greater. This machine design expounds on the positive features of a rotary deposition system<sup>[4]</sup> constructed previously for MLLs and contains multiple stationary, horizontally-oriented magnetron sources. A precision linear motion system raster scans a substrate over shaped apertures at well-defined velocities to affect a multilayer coating. An overview of the various types of MLL and current status, a plan forward, and the deposition laboratory equipment will be discussed.

<sup>\*</sup> rconley@bnl.gov